
British Standard Specification for

Harmonized system of quality assessment for
electronic components:

Capability detail specification: Single and
double sided printed boards with plain holes

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Foreword

This British Standard has been prepared under the direction of the Electronic Components Standards Policy Committee. It is a capability detail specification (Cap DS) within the BS CECC system and should be read in conjunction with BS CECC 23100.

It has been produced to reflect the capability levels established in the United Kingdom for the supply of printed boards to the defence, computer, communications and similar industries over many years. It is generally equivalent to that defined by BS 9000 'General requirements for a system for electronic components of assessed quality', and in particular by BS 9763 'Sectional specification for capability approval of manufacturers of single- and double-sided printed wiring boards of assessed quality without plated through holes.'

The capability level defined is enhanced compared to that described by BS CECC 23100-800. In particular capability has been extended to include the following:

- (a) more surface finishes, now split into two groups and referred to the connector area and the remainder of the board respectively;
- (b) more metallic finishes;
- (c) organic finishes used as solder resist;
- (d) marking inks;
- (e) bonded heatsinks;
- (f) accelerated ageing;
- (g) additional capability in the definition of minimum conductor and spacing widths;
- (h) traceability.

Cross-references

International standard	Corresponding British Standard
CECC 23000 : 1985	BS CECC 23000 : 1989 Harmonized system of quality assessment for electronic components : Generic specification : Printed boards (Identical)
CECC 23100 : 1985	BS CECC 23100 : 1989 Harmonized system of quality assessment for electronic components : Sectional specification : Single and double sided printed boards with plain holes (Identical)
IEC 68	BS 2011 Environmental testing (Most Parts are identical)
IEC 249	BS 4584 Metal-clad base materials for printed wiring boards (Most Parts are identical)
ISO 3543 : 1981	BS 5411 Methods of test for metallic and related coatings Part 12 : 1981 Beta backscatter method for measurement of thickness (Identical)

There is no British Standard equivalent to CECC 00010 : 1980 which comprises a list of the tests in IEC 326-2 and its supplement IEC 326-2A. A related British Standard to IEC 326-2 and its supplements is BS 6221 : Part 2 and its amendments.

Technical Committee has reviewed the provisions of CECC 13200 and ISO 3543 : 1982, to which reference is made in the text, and has decided that they are acceptable for use in conjunction with this standard.

Compliance with a British Standard does not of itself confer immunity from legal obligations.

Amendment No. 1
published and effective from 15 December 1992
to BS CECC 23100-003 : 1991

Specification for harmonized system of quality
assessment for electronic components:
Capability detail specification: Single and
double sided printed boards with plain holes

Corrections

AMD 7359
December 1992

Table I. Capability approval test schedule

In the entry for Thickness of plating: contact areas, in the requirements/material column, lines 3 to 4, delete 'Test method: ISO 3543-1981' and substitute the following.

'Test method:
ISO 3543-1981 or
ISO 1643-1982 (referee)'

AMD 7359
December 1992

Table IIb. Additional contact finishes

In the entry for Thickness of plating: contact areas, in the requirements/material column, lines 3 to 4, delete 'Test method: ISO 3543-1981' and substitute the following.

'Test method:
ISO 3543-1981 or
ISO 1643-1982 (referee)'

AMD 7359
December 1992

Clause C2. Adhesion of plating: Tape method

In paragraph 4, line 1, delete 'laid' and substitute 'laid'.

Amendment No. 2
published and effective from 15 January 1994
to BS CECC 23100-003 : 1991

**Specification for harmonized system of quality
assessment for electronic components: Capability detail
specification: Single and double sided printed boards
with plain holes**

Revised text

Clause 2.2.1 Metallic finishes

17	Tin-lead (roller coated)	SnPb(rt)
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In the final paragraph, line 1, delete '15 or 16' and substitute '15, 16 or 17'

AMD 7981/January 1994

Clause 3.1 Range of capability approval

After line 9, the entry for finish group 16, insert the following.

'finish group 17 covers finish group 11 and 17'

AMD 7981/January 1994

1 General

1.1 Scope

This Capability Detail Specification is based on CECC 23100. It relates to single and double sided printed boards with plain holes made with materials and surface finishes as specified in 2.

1.2 Object

To specify the Capability Qualifying Component 'CQC', its characteristics to be tested, the test methods and conditions to be applied and the requirements to be fulfilled for testing basic and extended capability.

2 Capability Qualifying Component (CQC)

Test boards to be used as CQCs for basic capability shall

- be made of one of the copper clad base materials specified in 2.1 of this Capability Detail Specification, base material thickness of 1.6 ± 0.14 mm and 35 μ m copper foil on both sides;
- bear the composite test pattern (CTP) specified in 8.2 of CECC 23100, (or equivalent composite test pattern);
- have one of the surface finishes specified by groups 11, 12, 13, 14, 15 or 16 in 2.2 of this Capability Detail Specification.

Test boards to be used as CQCs for additional capability shall be modified to demonstrate the claimed features - see 5.

2.1 Materials

Material group designation	Specification IEC	Base material		Base material thickness range mm	Cu-thickness μ m
		Type	Grade		
A	249-2-1	Phenolic paper	High electrical	0.2...6.4	18, 35, 70, 105
	249-2-2	Phenolic paper	Economic		
	249-2-6	Phenolic paper	Defined flammability (horizontal)		
	249-2-7	Phenolic paper	Defined flammability (vertical)		
	249-2-3	Epoxide paper	Defined flammability (vertical)		
B	249-2-4	Epoxide woven glass	General	0.2...6.4	18, 35, 70, 105
	249-2-5	Epoxide woven glass	Defined flammability (vertical)		

2.2 Surface finishes

2.2.1 Metallic finishes

Finish group designation	Surface finish	Abbreviation for QPL
11	Bare copper	Cu
12	Copper with temporary protective coating	Cu(tpc)
13	Copper with oxide	Cu(CuO)
14	Tin, tin-lead	Sn, SnPb
15	Tin-lead (fused)	SnPb(f)
16	Tin-lead (dipped and levelled)	SnPb(dl)

21	Specimen K 5 µm min. gold plated on copper, remainder using finish group 11 - 16 (see below)	5 Au/Cu, Cu, Sn, SnPb
22	Specimen K 0.7 µm min. gold plate on nickel, remainder using finish group 11 - 16 (see below)	0.7 Au/Ni, Cu, Sn, SnPb
23	Specimen K 2.5 µm min. gold plated on copper, remainder using finish group 11 - 16 (see below)	2.5 Au/Cu, Cu, Sn, SnPb
24	Specimen K 2.5 µm min. gold plate on nickel, remainder using finish group 11 - 16 (see below)	2.5 Au/Ni, Cu, Sn, SnPb

The demonstration of metallic finish groups 21, 22, 23 or 24 shall be combined with a finish from groups 11, 12, 13, 14, 15 or 16. Each claimed combination of metallic finishes shall be tested separately.

2.2.1.1 Accelerated ageing

The ability of finishes from groups 11, 12, 13, 14, 15 or 16 to solder after extended or adverse storage conditions is demonstrated using accelerated ageing. This test shall be carried out on those finishes where accelerated ageing is claimed. Each finish that has complied with the requirements of the accelerated ageing test is highlighted by the inclusion of an asterisk (**) adjacent to that finish in the manufacturers abstract of capability as published in the QPL.

2.2.2 Organic finishes

Finish group designation	Organic finish	Abbreviation for QPL
a	Dryfilm solder mask	DSM
b	Wet resist solder mask	WSM
c	Liquid photo polymer solder mask	LSM
d	Marking inks	MI

The demonstration of organic finish groups a, b, c or d shall be over a finish from groups 11, 12, 13, 14, 15 or 16. All claimed types of solder resist and marking ink shall be tested separately.

2.3 Variant designation

The combination of any material group designated in 2.1 and any of the surface finishes as designated in 2.2 constitutes a variant. The variant is designated by the combination of material and finish group designations e.g. A12(b) or A12/21(c).

3 Capability approval

3.1 Range of capability approval

Capability approval granted on the testing of one variant is valid within the limits specified in 3.7 of CECC 23000 for

- metal-clad base material within one group designation, all base material thicknesses and all foil thicknesses of the material in accordance with 2.1; and
- all metallic surface finishes within one surface finish group as quoted in 2.2.1, that is

finish group 11	covers finish group 11 only
finish group 12	covers finish group 11 and 12
finish group 13	covers finish group 11 and 13
finish group 14	covers finish group 11 and 14
finish group 15	covers finish group 11 and 15
finish group 16	covers finish group 11 and 16
finish group 21	covers finish group 21 only
finish group 22	covers finish group 22 and 24
finish group 23	covers finish group 21 and 23
finish group 24	covers finish group 24 only

3.2 QPL information

The QPL information shall be given in accordance with 3.4 of CECC 23000 and shall contain the following details:

- Reference to the CECC Generic Specification : 23000
- Reference to the CECC Sectional Specification : 23100
- Reference to the BS CECC Capability Detail Specification : BS 23100-003
- Base material for which approval is granted as given in 2.1
- The surface finishes for which approval is granted as given in 2.2
- Any additional capability, 3.5.3 of CECC 23000 refers

Capability test programme

Each separate process shall be assessed within the test programme.

The number of failures permitted for each test is specified in the following tables but the total for any CQC shall not exceed 3 (as permitted in CECC 23200 Table III).

3.1 Capability demonstration

Capability shall be demonstrated by using 9 composite test patterns (CTPs) of one variant from each material group claimed. Testing shall be in accordance with Table I.

3.1.1 Other metallic surface finishes

claimed, other metallic surface finishes, as designated in 2.2.1, shall be demonstrated by the manufacture of 3 CTPs plus sufficient extra A and H specimens to meet the requirements of Table II. Testing shall be in accordance with Table II.

- Note:-
1. The maximum claimed active board size for the finish shall be demonstrated.
 2. Demonstration of metallic surface finishes using materials from group A apply to that group only.
Demonstration of metallic surface finishes using materials from group B also covers their application to materials from group A.

4.1.2 Organic surface finishes

Each claimed organic surface finish, as designated in 2.2.2, shall be demonstrated by the manufacture of 3 CTPs using the pattern specified in Appendix A (marking inks) or Appendix B (solder masks). Testing shall be in accordance with Table III.

- Note:-
- Demonstration of organic surface finishes using material from group A apply to that group only.
 - Demonstration of organic surface finishes using material from group B also covers their application to materials from group A.

5 Additional capability

Maximum active board size (mm) - length and breadth - see 8.3 of CECC 23100.

Minimum conductor width - Specimen F of CTP to be modified to provide additionally 5 conductors and 4 spacings, each of the claimed minimum.
and spacing Initial foil thickness of less than 35 µm may be used for this demonstration but this thickness shall be declared.

6 Traceability

Traceability of all test specimens to the original production panel shall be maintained. The method used to identify individual test specimens shall not affect the test result.